



中国认可
国际互认
检测
TESTING
CNAS L14228

Ref.No	ACSH22101101-R02
Total pages	7

Test Report

Product name: Silicone keyboard

Model Specifications: K-TEK-M275TP-FN-BL-NV-EMC-151B

Detection category: Commissioned trial

production unit: Key Technology (China) Limited

Requester: Key Technology (China) Limited



ANCHESHENGHUI

安车昇辉

Shenzhen Ancheshenghui Test Technology Co., Ltd.

Test Report

Client information

Name: Key Technology (China) Limited

Address: Floor 7, Building S8, Fenggang Tianan Cyber Park, No. 208 Fenggang Section, Dongshen Road, Fenggang Town, Dongguan City, Guang Dong Province, P.R. China.

Unit of production

Name: Key Technology (China) Limited

Address: Floor 7, Building S8, Fenggang Tianan Cyber Park, No. 208 Fenggang Section, Dongshen Road, Fenggang Town, Dongguan City, Guang Dong Province, P.R. China

Company headquarters of the entrusting unit

Name: Key Technology (China) Limited

Address: B703, Building 1, Tianan Cyber Park, Huang Ge North Rd, Longcheng Subdistrict, Long Gang District, ShenZhen, Guang Dong Province, P.R. China.

Sample

Sample name: Silicone keyboard

Sample model: K-TEK-M275TP-FN-BL-NV-EMC-151B

Sample serial number: ACSH22101101-S01~03

Number of samples: 3 pcs

Production unit: Key Technology (China) Limited

Sample pick up date: October 11, 2022

Source: sample sent by the entrusting party

Describe: The sample appeared in good condition at the time of sampling

Testing location and environment

Testing location: Shenzhen Anche Shenghui Testing Technology Co., Ltd.

Temperature: 21°C~28°C Relative Humidity: 45%~75% Air Pressure: 100kPa~102kPa

Testing base

1) GJB 150.1A-2009

2) GJB 150.4A-2009

Test results

Samples commissioned by Key Technology (China) Limited: Silicone Keyboard K-TEK-M275TP-FN-BL-NV-EMC-151B, According to the testing requirements of the client, the low temperature test was conducted from October 11, 2022 to October 13, 2022.

After the test, the samples meet the technical requirements in GJB 150.4A-2009 standard, and the test is qualified.

For details of the test, see Summary of Test Results.

J He

Prepared by

Hq Wang

Reviewed by



Release date: November 01, 2022

Summary of test results

Sequence	Test Items	Test Date	Detection Location	Result
1	Low Temperature	2022.10.11-2022.10.13	Environmental Laboratory	Pass
Detailed description of test results				
After the test, the appearance and structure of the sample are not damaged, the sample performance test is normal, and the test is qualified.				

Detailed description of the test sample

Item	Name	Model	Quantity	Numbering
1	Silicone keyboard	K-TEK-M275TP-FN-BL-NV-EMC-151B	3pcs	ACSH22101101-S01~03

Detection details

1. Low Temperature

1.1 Test samples

Item	Name	Model	Quantity	Numbering
1	Silicone keyboard	K-TEK-M275TP-FN-BL-NV-EMC-151B	3pcs	ACSH22101101-S01~03

1.2 Testing equipment and instruments

Item	Name	Model	Numbering	Validity Of Measurement Until	Remark
1	High and low temperature humid heat test chamber	HSL-10KA	ACSH-A-003	2023-10-15	/

1.3 Testing base

1) GJB 150.1A-2009 Military equipment laboratory environmental test methods - Part 1: General requirements;

2) GJB 150.4A-2009 Military equipment laboratory environmental test methods - Part 4: Low temperature test;

1.4 Test time

2022.10.11-2022.10.13

1.5 Conditions of test

Conduct tests as required by client. The test methods are as follows:

a) Pre-test inspection: under standard atmospheric conditions, the appearance inspection and performance inspection of the tested products are carried out;

b) Test:

1) Test temperature: -55℃ (procedure I storage);

2) Test time: 24h;

3) Test temperature: -40℃ (program II operation);

4) Test time: 4h;

5) Sample status in the test: (Procedure I storage) the sample does not work during the test, (procedure II work) the sample is powered on during the test;

6) Whether functional testing is carried out in the test: Yes;

c) Post-test detection: under standard atmospheric conditions, the appearance inspection and performance inspection of the tested products are carried out.

1.6 Eligibility criteria

After the test, the appearance and structure of the sample have no obvious damage, and the performance test is normal.

1.7 Detect photos and curves



Figure 1 Sample appearance (before test)



Figure 2 Sample placement status



Figure 3 Sample working condition



Figure 4 Performance test

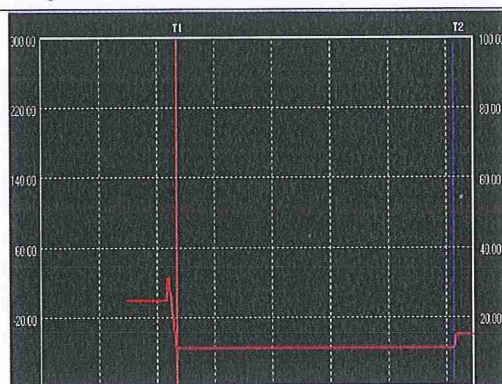


Figure 5 Procedure I storage test curve

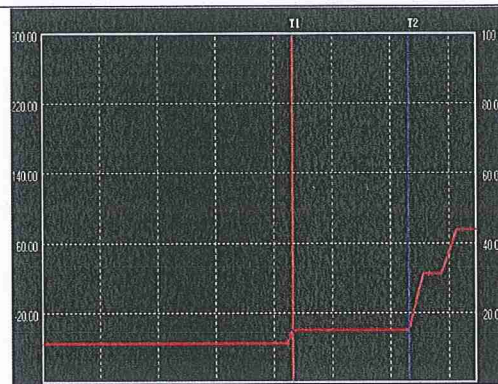


Figure 6 Program II Working test curve

1.8 Test results

After the test, the appearance and structure of the sample have no obvious damage, the performance test is normal, the test is qualified.

(End, there is no test report content below)

Precautions

1. The report has no "special seal for testing" or the official seal of the testing unit is invalid.
2. The report is invalid if it is not re-stamped with the "special seal for testing" or the official seal of the testing unit.
3. The report is invalid if without the signature of the person who prepared, reviewed and approved it.
4. The report is invalid if it is altered.
5. Projects marked with * are not within the scope of our CNAS accreditation.
6. If there is any objection to the test report, it should be submitted to the test unit within 15 days from the date of receipt of the report, and it will not be accepted after the expiration date.
7. The entrusted test results are only responsible for the incoming samples.

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